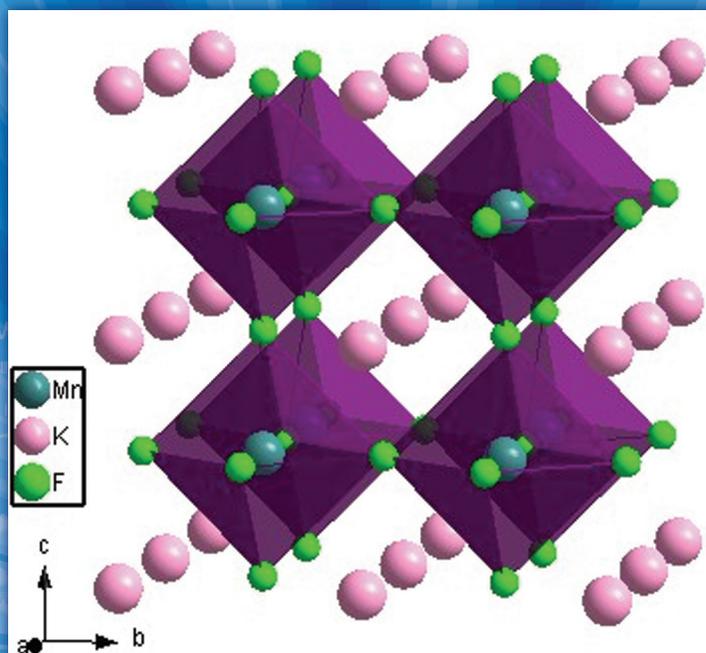


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Powder Diffraction

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On the Cover: Figure 3: Crystal structure of KMF_3 ($M = Mn, Co, Ni$).
(Courtesy of Shunli Wang.)

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